



Edition 1.0 2010-05

TECHNICAL REPORT



Dynamic modules Teh STANDARD PREVIEW Part 6-3: Round robin measurement results for group delay ripple of tunable dispersion compensators (Standards.iteh.ai)





THIS PUBLICATION IS COPYRIGHT PROTECTED

Copyright © 2010 IEC, Geneva, Switzerland

All rights reserved. Unless otherwise specified, no part of this publication may be reproduced or utilized in any form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from either IEC or IEC's member National Committee in the country of the requester.

If you have any questions about IEC copyright or have an enquiry about obtaining additional rights to this publication, please contact the address below or your local IEC member National Committee for further information.

Droits de reproduction réservés. Sauf indication contraire, aucune partie de cette publication ne peut être reproduite ni utilisée sous quelque forme que ce soit et par aucun procédé, électronique ou mécanique, y compris la photocopie et les microfilms, sans l'accord écrit de la CEI ou du Comité national de la CEI du pays du demandeur.

Si vous avez des questions sur le copyright de la CEI ou si vous désirez obtenir des droits supplémentaires sur cette publication, utilisez les coordonnées ci-après ou contactez le Comité national de la CEI de votre pays de résidence.

IEC Central Office 3, rue de Varembé CH-1211 Geneva 20 Switzerland

Email: inmail@iec.ch Web: www.iec.ch

About IEC publications

The technical content of IEC publications is kept under constant review by the IEC. Please make sure that you have the latest edition, a corrigenda or an amendment might have been published.

■ Catalogue of IEC publications: www.iec.ch/searchpub

The IEC on-line Catalogue enables you to search by a variety of criteria (reference number, text, technical committee,...). It also gives information on projects, withdrawn and replaced publications.

■ IEC Just Published: www.iec.ch/online_news/justpub) A Published details twice a month all new publications released. Available on-line and also by email.

■ Electropedia: www.electropedia.org (Standards.Iten.al)

The world's leading online dictionary of electronic and electrical terms containing more than 20 000 terms and definitions in English and French, with equivalent terms in additional languages. Also known as the International Electrotechnical Vocabulary online.

Customer Service Centre: https://standards.itel.ai/catalog/standards/sist/a4d4f9d3-cd86-4bc9-9ebc-www.iec.ch/webstore/custserv

Customer Service Centre: https://standards.itel.ai/catalog/standards/sist/a4d4f9d3-cd86-4bc9-9ebc-www.iec.ch/webstore/custserv

Control of the control of t

If you wish to give us your feedback on this publication or need further assistance, please visit the Customer Service Centre FAQ or contact us:

Email: <u>csc@iec.ch</u> Tel.: +41 22 919 02 11 Fax: +41 22 919 03 00



IEC/TR 62343-6-3

Edition 1.0 2010-05

TECHNICAL REPORT



Dynamic modulesiTeh STANDARD PREVIEW

Part 6-3: Round robin measurement results for group delay ripple of tunable dispersion compensators

IEC TR 62343-6-3:2010

https://standards.iteh.ai/catalog/standards/sist/a4d4f9d3-cd86-4bc9-9ebc-6cda02d50ca9/iec-tr-62343-6-3-2010

INTERNATIONAL ELECTROTECHNICAL COMMISSION

PRICE CODE



ICS 33.180

ISBN 978-2-88910-992-0

CONTENTS

FO	REWO	DRD	4		
INT	RODI	JCTION	6		
1	Scop	e	7		
2	Normative references				
3	Abbr	eviated terms	7		
4	Types of tunable dispersion compensators (TDCs)				
	4.1	Virtual imaged phased array (VIPA)	8		
	4.2	Fibre Bragg grating (FBG)	8		
	4.3	Planar lightwave circuit (PLC)			
	4.4	Etalon			
5	Measurement methods				
	5.1	Modulation phase shift (MPS) method			
	5.2	Modulation phase shift-Mueller matrix (MPS-Mueller) method			
	5.3 5.4	Polarization phase shift (PPS) method			
6	_	Swept wavelength interferometry (SWI) methods and test parameters			
7		surement results			
′	7.1	VIPAiTeh STANDARD PREVIEW			
	7.1	FRG	1		
	7.3	PLC (standards.iteh.ai)	16		
8	Data	Etalon	21		
	8.1	Repeatability6cda02d50ca9/icc-tr-62343-6-3-2010	21		
	8.2	Measurement method differences			
9	Cons	ideration of phase ripple	24		
10	Conc	Conclusion			
Fig	ure 1	- Structure of the VIPA	8		
Fig	ure 2	Chirped fibre grating	8		
Fig	ure 3	- PLC (MZ interference circuit)	9		
Fig	ure 4	– Etalon (Gires-Tournois interferometer)	9		
Fig	ure 5	– GD and IL of the VIPA	12		
Fig	ure 6	GD deviation with each measurement method of the VIPA	12		
Fig	ure 7	GD deviation at different RBWs of the VIPA	13		
Fig	ure 8	Summary of GDR measurement results of the VIPA	13		
Fig	ure 9	- Summary of GDR repeatability of the VIPA	14		
Fig	ure 10) – GD and IL of FBG1	14		
		- GD deviation with each measurement method of FBG1			
Fig	ure 11	i – GD deviation with each measurement method of FBG i	15		
_					
Fig	ure 12	2 – GD deviation at different RBWs of FBG1	15		
Fig Fig	ure 12 ure 13	2 – GD deviation at different RBWs of FBG1	15 16		
Fig Fig Fig	ure 12 ure 13 ure 14	2 – GD deviation at different RBWs of FBG1	15 16		

Figure 17 – GD deviation of the PLC at different RBWs	18
Figure 18 – Summary of GDR measurement results of the PLC	18
Figure 19 – Summary of GDR repeatability of the PLC	19
Figure 20 – GD and IL of the etalon	19
Figure 21 – GD deviation of the etalon with different measurement methods	20
Figure 22 – GD deviation of the etalon at different RBWs	20
Figure 23 – Summary of GDR measurement results of the etalon	21
Figure 24 – Summary of GDR repeatability of the etalon	21
Figure 25 – RBW, measurement methods and GDR repeatability	22
Figure 26 – Differences in GDR measurement results between measurement methods	23
Figure 27 – GDR differences produced when measuring a TDC with GDR of less than 6 ps at RBW of 8 pm	23
Figure 28 – Typical measurement result of GDR	24
Figure 29 – Phase ripple calculated from GDR	25
Figure 30 – Amplitude, period, and EOP of GDR	25
Figure 31 – Phase ripple of the VIPA and FBGs	26
Figure 32 – Phase ripple repeatability of the VIPA and FBGs	26
Figure 33 – Differences in phase ripple between measurement methods iTeh STANDARD PREVIEW	27
Table 1 – DUTs and measurement methods used in round robin testing	10
Table 2 – RBW and modulation frequency	11

INTERNATIONAL ELECTROTECHNICAL COMMISSION

DYNAMIC MODULES -

Part 6-3: Round robin measurement results for group delay ripple of tunable dispersion compensators

FOREWORD

- 1) The International Electrotechnical Commission (IEC) is a worldwide organization for standardization comprising all national electrotechnical committees (IEC National Committees). The object of IEC is to promote international co-operation on all questions concerning standardization in the electrical and electronic fields. To this end and in addition to other activities, IEC publishes International Standards, Technical Specifications, Technical Reports, Publicly Available Specifications (PAS) and Guides (hereafter referred to as "IEC Publication(s)"). Their preparation is entrusted to technical committees; any IEC National Committee interested in the subject dealt with may participate in this preparatory work. International, governmental and non-governmental organizations liaising with the IEC also participate in this preparation. IEC collaborates closely with the International Organization for Standardization (ISO) in accordance with conditions determined by agreement between the two organizations.
- 2) The formal decisions or agreements of IEC on technical matters express, as nearly as possible, an international consensus of opinion on the relevant subjects since each technical committee has representation from all interested IEC National Committees.
- 3) IEC Publications have the form of recommendations for international use and are accepted by IEC National Committees in that sense. While all reasonable efforts are made to ensure that the technical content of IEC Publications is accurate, IEC cannot be held responsible for the way in which they are used or for any misinterpretation by any end user.
- 4) In order to promote international uniformity, EC National Committees undertake to apply IEC Publications transparently to the maximum extent possible in their national and regional publications. Any divergence between any IEC Publication and the corresponding national or regional publication shall be clearly indicated in the latter
- https://standards.iteh.ai/catalog/standards/sist/a4d4f9d3-cd86-4bc9-9cbc5) IEC itself does not provide any attestation of conformity. Independent certification bodies provide conformity assessment services and, in some areas, access to IEC marks of conformity. IEC is not responsible for any services carried out by independent certification bodies.
- 6) All users should ensure that they have the latest edition of this publication.
- 7) No liability shall attach to IEC or its directors, employees, servants or agents including individual experts and members of its technical committees and IEC National Committees for any personal injury, property damage or other damage of any nature whatsoever, whether direct or indirect, or for costs (including legal fees) and expenses arising out of the publication, use of, or reliance upon, this IEC Publication or any other IEC Publications.
- 8) Attention is drawn to the Normative references cited in this publication. Use of the referenced publications is indispensable for the correct application of this publication.
- 9) Attention is drawn to the possibility that some of the elements of this IEC Publication may be the subject of patent rights. IEC shall not be held responsible for identifying any or all such patent rights.

The main task of IEC technical committees is to prepare International Standards. However, a technical committee may propose the publication of a technical report when it has collected data of a different kind from that which is normally published as an International Standard, for example "state of the art".

IEC 62343-6-3, which is a technical report, has been prepared by subcommittee 86C: Fibre optic systems and active devices, of IEC technical committee 86: Fibre optics.

The text of this technical report is based on the following documents:

Enquiry draft	Report on voting
86C/917/DTR	86C/952/RVC

Full information on the voting for the approval of this technical report can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts of IEC 62343 series, published under the general title *Dynamic modules*, can be found on the IEC website.

The committee has decided that the contents of this publication will remain unchanged until the stability date indicated on the IEC web site under "http://webstore.iec.ch" in the data related to the specific publication. At this date, the publication will be

- · reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- · amended.

A bilingual version of this publication may be issued at a later date.

IMPORTANT – The 'colour inside' logo on the cover page of this publication indicates that it contains colours which are considered to be useful for the correct understanding of its contents. Users should therefore print this document using a colour printer.

iTeh STANDARD PREVIEW (standards.iteh.ai)

INTRODUCTION

The most important means of enhancing the technology for communication systems are networking, faster speed, and longer distance. In long-distance, high-speed communication systems operating at 40 Gbps or more, dispersion is known to limit transmission distance. Various tunable dispersion compensators (TDCs) have been commercialized in order to minimize the degradation of signals caused by chromatic dispersion. However, the group delay (GD) in TDCs is known to have ripples dependent on the principles of TDC operation, and such GD affects signal degradation.

IEC TC86 (*Fibre optics*) describes several methods of measuring chromatic dispersion (CD). One example is IEC 61300-3-38, but it does not specify a measurement method for group delay ripple (GDR). The representative passive component for compensating for chromatic dispersion is dispersion compensation fibre (DCF), but given its principles, the GD has no ripples. Conversely, many TDCs use the interference effect, which explains why there are ripples.

Under these circumstances, round robin testing has been conducted by using various TDCs and diverse GD measurement methods. This technical report, based on the findings from round robin testing, examines the direction of standardization for GDR measurement methods.

This technical report is based on and translated from OITDA document- TP06/SP DM-2008 (Group Delay Ripple Measurement Method for Tunable Dispersion Compensators—Technical Paper).

Teh STANDARD PREVIEW

(standards.iteh.ai)

DYNAMIC MODULES -

Part 6-3: Round robin measurement results for group delay ripple of tunable dispersion compensators

1 Scope

This technical report describes the round robin measurement results for the group delay ripple (GDR) of tunable dispersion compensators (TDCs). It briefly explains the four typical TDCs measured and four typical methods of measuring group delay (GD), as well as the GDR round robin measurement results of TDCs, and an analysis of repeatability and differences among these measurement methods. This technical report also proposes suitable measurement parameters and a new parameter of phase ripple instead of GDR.

2 Normative references

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

iTeh STANDARD PREVIEW

IEC/PAS 61300-3-38, Fibre optic interconnecting devices and passive components – Basic test and measurement procedures – Part 3-38 Group delay and chromatic dispersion

IEC 62343-1-2, Dynamic modules – Part 16234Performance standards – Dynamic chromatic dispersion compensator with pigtails for use in controlled environments (Category C)

6cda02d50ca9/jec-tr-62343-6-3-2010

3 Abbreviated terms

For the purposes of this document, the abbreviated terms apply.

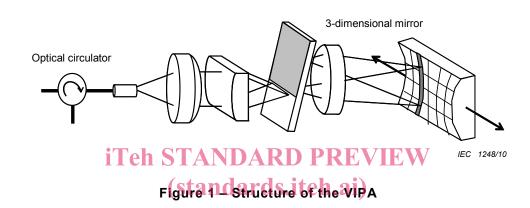
CD	chromatic dispersion
DGD	differential group delay
DUT	device under test
EOP	eye opening penalty
FBG	fibre Bragg grating
FSR	free spectral range
GD	group delay
GDR	group delay ripple
MPS	modulation phase shift
MZ	Mach-Zender
PLC	planar lightwave circuit
PPS	polarization phase shift
RBW	resolution bandwidth
SWI	swept wavelength interferometry
TDC	tunable dispersion compensator
VIPA	virtually imaged phased array

4 Types of tunable dispersion compensators (TDCs)

Various TDCs have been announced and commercialized in the market. The following briefly describes typical TDCs.

4.1 Virtual imaged phased array (VIPA)

Figure 1 shows the structure of a virtually imaged phased array (VIPA). The input light from a single-mode fibre is line-focused onto a glass plate. The glass plate is coated on both sides and collimated light is emitted from the reverse side of the glass after multiple reflections on the glass plate. The light from the glass plate is focused onto a curved mirror. The reflected light travels back to the glass plate and is finally coupled to the fibre. The 3-dimensional mirror is moved to vary the optical distance for each wavelength, thereby changing the CD.



4.2 Fibre Bragg grating (FBG) IEC TR 62343-6-3:2010

https://standards.iteh.ai/catalog/standards/sist/a4d4f9d3-cd86-4bc9-9ebc-

An FBG periodically changes the defraction index of the optical fibre core, thereby forming a grating to generate Bragg diffraction, which functions as a reflection filter. Gradually changing the pitch of Bragg diffraction varies the reflection return time according to wavelength, thereby generating CD. The temperature of the fibre formed in the FBG can be varied or given tension to change the FBG pitch. This principle is used to change the CD.

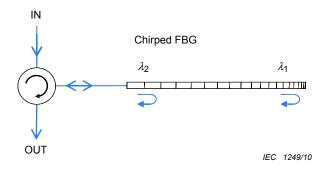


Figure 2 - Chirped fibre grating

4.3 Planar lightwave circuit (PLC)

A ring resonator can be formed on a quartz lightwave circuit. The resulting interference effect can then be used to produce periodic loss and GD characteristics over the wavelength. Moreover, the ring resonator can be replaced with MZ interference circuits in multiple stages to produce similar effects. The temperatures of some of these interference circuits can be varied to change the CD.

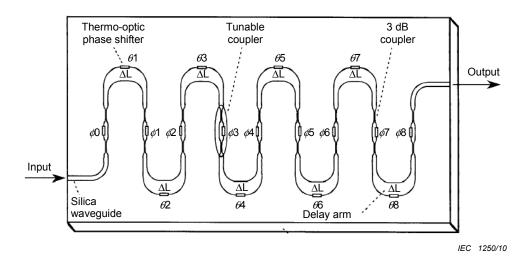


Figure 3 – PLC (MZ interference circuit)

4.4 Etalon

Etalon is an optical cavity housing a pair of parallel reflective mirrors. Multiple reflection interference between two filters yields a cyclic spectrum and dispersion characteristics. The period of the cyclic spectrum is called free spectral range (FSR). The operating wavelength and FSR can be adjusted by changing the optical distance between both mirrors. A Gires-Tournois interferometer (shown in Figure 4 below) is suitable for dispersion compensation.

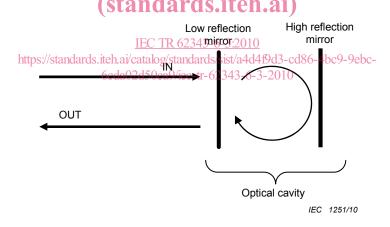


Figure 4 – Etalon (Gires-Tournois interferometer)

5 Measurement methods

The following describes the representative methods of measuring GD. Refer to IEC/PAS 61300-3-38 for details.

5.1 Modulation phase shift (MPS) method

The MPS method is used to calculate GD and CD by adding amplitude modulation to output light from a wavelength-variable light source, receiving it with a receiver through a device under test (DUT), and then analyzing the wavelength dependence of the phase of the demodulated signal received. The wavelength resolution depends on the signal's modulation frequency. Because there is a trade-off between wavelength resolution and measurement accuracy, modulation frequency is an important measurement parameter.

5.2 Modulation phase shift-Mueller matrix (MPS-Mueller) method

The MPS-Mueller method combines the MPS method with a process to produce four polarization states of modulated light entering the DUT, and then solving the Mueller matrix for each phase calculated, thereby calculating GD and CD in an average polarization state. Similarly to the MPS method, modulation frequency becomes an important measurement parameter.

5.3 Polarization phase shift (PPS) method

The PPS method expands on the MPS method by adding hardware to divide the light beam transmitted through the DUT into two orthogonal polarized beams. The two polarization states are analyzed and GD and CD are calculated for an average polarization state. Similar to the MPS method, modulation frequency becomes an important measurement parameter.

5.4 Swept wavelength interferometry (SWI) method

Unlike the method above, the SWI method does not modulate the light beams measured. The wavelength of the wavelength-varied light source is swept before entering the receiver via the Mach-Zehnder (MZ) interferometer. With two paths through the MZ interferometer, one as the reference path and one through the interfered signal into the receiver are analyzed to determine the phase of light. The resultant findings are then used to calculate GD and CD. That is how this method works. Since the setting of wavelength resolution and measurement accuracy can be changed to oppose each other, wavelength resolution becomes an important measurement parameter.

6 DUTs and test parameterstandards.iteh.ai)

Table 1 lists the DUTs measured and the measurement methods used. For the MPS and SWI methods, products from two different manufacturers identified as (A) and (B), respectively, were used depending on the test date of the PPS and MPS (A) methods used the same measuring equipment, with only the measurement method being switched over. The same is true of the MPS-Mueller and MPS (B) methods. Moreover, the SWI (A) method is based on a homodyne-type interferometer, while the SWI (B) method is based on a heterodyne-based interferometer.

Table 1 - DUTs and measurement methods used in round robin testing

DUTs	Measurement methods
VIPA	PPS, MPS (A), SWI (A)
FBG (1) FBG (2) FBG (3)	PPS, MPS (A), SWI (A) MPS-Mueller, PPS, MPS (A) MPS-Mueller, PPS, MPS (A)
PLC	MPS-Mueller, MPS (B), SWI (B)
Etalon	MPS-Mueller, MPS (B), SWI (B)

MPS (A) MPS mode of PPS test equipment

MPS (B) MPS mode of MPS-Mueller test equipment

SWI (A) Homodyne type

SWI (B) Heterodyne type